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	stitute for form 1449/PTO	Complete if Known			
		Application Number	10/685 518		
IN	FORMATION DISCLOSURE	Filing Date	October 16, 2003		
		First Named Inventor	Chul-Sung KIM, et al		
S	TATEMENT BY APPLICANT	Art Unit	2824	· · · · ·	
	(Use as many sheets as necessary)	Examiner Name	C. WILSON		
Sheet	1 of 2	Attorney Docket Number	239/162 DIV.2		

	1			DOCUMENTS	· • · · · · · · · · · · · · · · · · · ·
Examiner Initials*	Cite No.	Document Number Number-Kind Code ² (F Innount)	Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear
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	FOREIGN PATENT DOCUMENTS								
Examiner Initials*	Cite No.1	Foreign Patent Document	Publication Date	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines, Where Relevant Passages	Π			
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Substitute for form 1449/PTO		Compl te if Known			
			Application Numb r	10/685,518	
INFORMATIO			Filing Date	October 16, 2003	
STATEMENT	BY A	PPLICANT	First Named Inventor	Chul-Sung KIM, et al	
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(000 to many o			Examiner Name	C. WILSON	
Sheet 2	of	2	Attorney Docket Number	239/162 DIV.2	

		NON PATENT LITERATURE DOCUMENTS	
Examiner Initials*	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-number(s), publisher, city and/or country where published.		Τ²
S		WOLF, et al., Silicon Processing for the VLSI Era, Vol 1, Process Technology, Lattice Press, p.201	
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Signature	Christia	Wilson	Cor	nsidered S/18	(14) 4

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